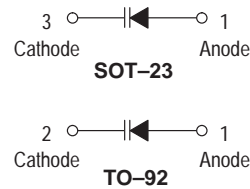


## Silicon Tuning Diodes

These devices are designed in the popular PLASTIC PACKAGE for high volume requirements of FM Radio and TV tuning and AFC, general frequency control and tuning applications. They provide solid-state reliability in replacement of mechanical tuning methods. Also available in Surface Mount Package up to 33pF.

- High Q
- Controlled and Uniform Tuning Ratio
- Standard Capacitance Tolerance — 10%
- Complete Typical Design Curves



**MMBV2101LT1**  
**MMBV2103LT1**  
**MMBV2105LT1**  
**MMBV2107LT1**  
**MMBV2108LT1**  
**MMBV2109LT1**  
**MV2101 MV2104**  
**MV2105 MV2108**  
**MV2109 MV2111**  
**MV2115**

**6.8–100 pF**  
**30 VOLTS**  
**VOLTAGE VARIABLE**  
**CAPACITANCE DIODES**

### MAXIMUM RATINGS

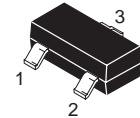
Rating	Symbol	MV21xx	MMBV21xxLT1	Unit
Reverse Voltage	$V_R$	30		Vdc
Forward Current	$I_F$	200		mA <sub>dc</sub>
Forward Power Dissipation @ $T_A = 25^\circ\text{C}$ Derate above $25^\circ\text{C}$	$P_D$	280 2.8	225 1.8	mW mW/ $^\circ\text{C}$
Junction Temperature	$T_J$	+150		$^\circ\text{C}$
Storage Temperature Range	$T_{stg}$	-55 to +150		$^\circ\text{C}$

### DEVICE MARKING

MMBV2101LT1 = M4G	MMBV2107LT1 = 4W
MMBV2103LT1 = 4H	MMBV2108LT1 = 4X
MMBV2105LT1 = 4U	MMBV2109LT1 = 4J

### ELECTRICAL CHARACTERISTICS ( $T_A = 25^\circ\text{C}$ unless otherwise noted)

Characteristic	Symbol	Min	Typ	Max	Unit
Reverse Breakdown Voltage ( $I_R = 10 \mu\text{A}_{dc}$ )	$V_{(BR)R}$	30	—	—	Vdc
Reverse Voltage Leakage Current ( $V_R = 25 \text{ Vdc}$ , $T_A = 25^\circ\text{C}$ )	$I_R$	—	—	0.1	$\mu\text{A}_{dc}$
Diode Capacitance Temperature Coefficient ( $V_R = 4.0 \text{ Vdc}$ , $f = 1.0 \text{ MHz}$ )	$TC_C$	—	280	—	ppm/ $^\circ\text{C}$



**CASE 318-08, STYLE 8**  
**SOT-23 (TO-236AB)**



**CASE 182-02, STYLE 1**  
**TO-92 (TO-226AC)**

Device	C <sub>T</sub> , Diode Capacitance V <sub>R</sub> = 4.0 Vdc, f = 1.0 MHz pF			Q, Figure of Merit V <sub>R</sub> = 4.0 Vdc, f = 50 MHz	TR, Tuning Ratio C <sub>2</sub> /C <sub>30</sub> f = 1.0 MHz		
	Min	Nom	Max	Typ	Min	Typ	Max
MMBV2101LT1/MV2101	6.1	6.8	7.5	450	2.5	2.7	3.2
MMBV2103LT1	9.0	10	11	400	2.5	2.9	3.2
MV2104	10.8	12	13.2	400	2.5	2.9	3.2
MMBV2105LT1/MV2105	13.5	15	16.5	400	2.5	2.9	3.2
MMBV2107LT1	19.8	22	24.2	350	2.5	2.9	3.2
MMBV2108LT1/MV2108	24.3	27	29.7	300	2.5	3.0	3.2
MMBV2109LT1/MV2109	29.7	33	36.3	200	2.5	3.0	3.2
MV2111	42.3	47	51.7	150	2.5	3.0	3.2
MV2115	90	100	110	100	2.6	3.0	3.3

MMBV2101LT1, MMBV2103LT1, MMBV2105LT1, MMBV2107LT1 thru MMBV2109LT1, are also available in bulk. Use the device title and drop the "T1" suffix when ordering any of these devices in bulk.

### PARAMETER TEST METHODS

#### 1. C<sub>T</sub>, DIODE CAPACITANCE

(C<sub>T</sub> = C<sub>C</sub> + C<sub>J</sub>). C<sub>T</sub> is measured at 1.0 MHz using a capacitance bridge (Boonton Electronics Model 75A or equivalent).

#### 2. TR, TUNING RATIO

TR is the ratio of C<sub>T</sub> measured at 2.0 Vdc divided by C<sub>T</sub> measured at 30 Vdc.

#### 3. Q, FIGURE OF MERIT

Q is calculated by taking the G and C readings of an admittance bridge at the specified frequency and substituting in the following equations:

$$Q = \frac{2\pi fC}{G}$$

(Boonton Electronics Model 33AS8 or equivalent). Use Lead Length ≈ 1/16".

#### 4. TCC, DIODE CAPACITANCE TEMPERATURE COEFFICIENT

TCC is guaranteed by comparing C<sub>T</sub> at V<sub>R</sub> = 4.0 Vdc, f = 1.0 MHz, T<sub>A</sub> = -65°C with C<sub>T</sub> at V<sub>R</sub> = 4.0 Vdc, f = 1.0 MHz, T<sub>A</sub> = +85°C in the following equation, which defines TCC:

$$TCC = \left| \frac{C_T(+85^\circ\text{C}) - C_T(-65^\circ\text{C})}{85 + 65} \right| \cdot \frac{10^6}{C_T(25^\circ\text{C})}$$

Accuracy limited by measurement of C<sub>T</sub> to ±0.1 pF.

TYPICAL DEVICE CHARACTERISTICS

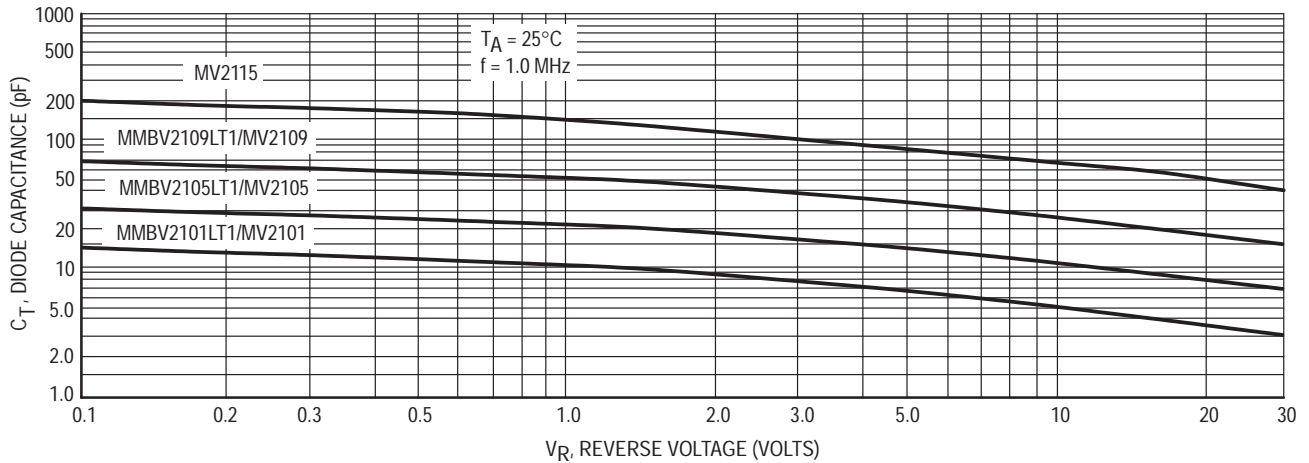


Figure 1. Diode Capacitance versus Reverse Voltage

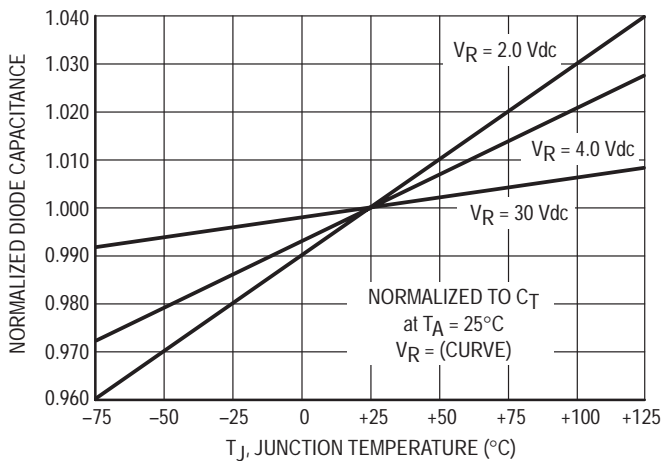


Figure 2. Normalized Diode Capacitance versus Junction Temperature

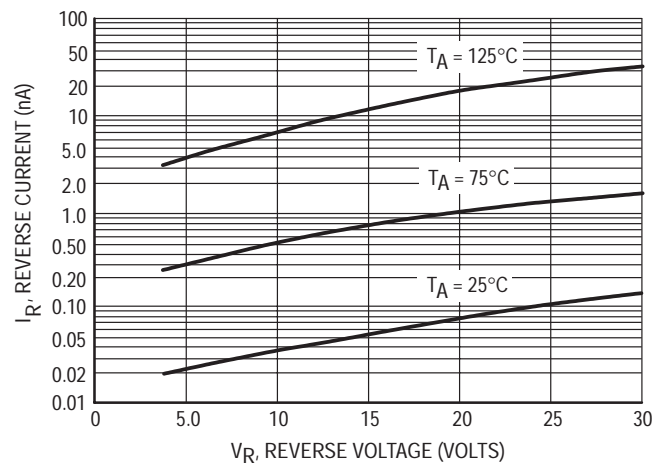


Figure 3. Reverse Current versus Reverse Bias Voltage

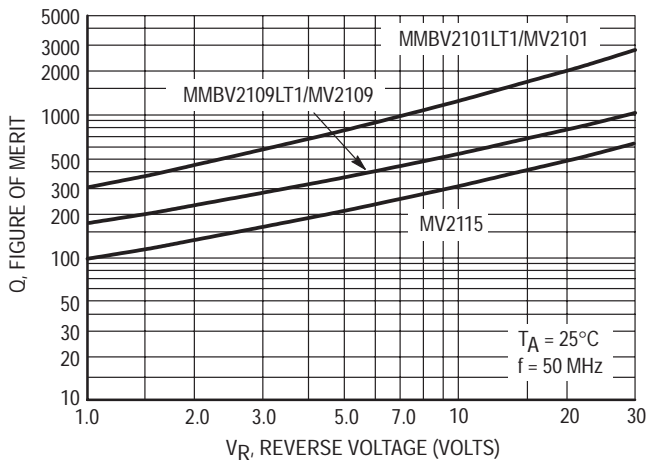


Figure 4. Figure of Merit versus Reverse Voltage

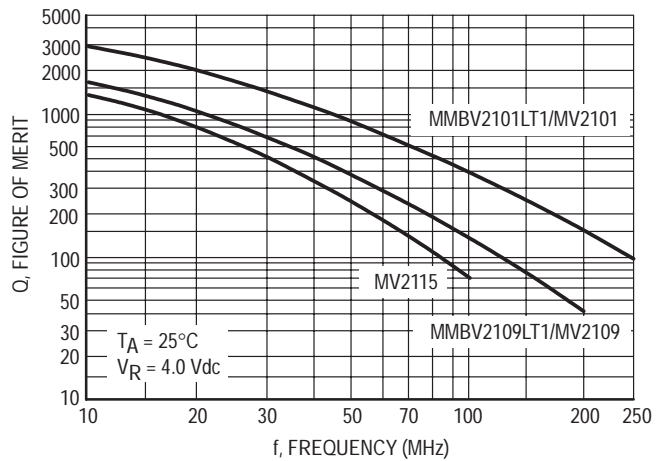


Figure 5. Figure of Merit versus Frequency